Search Notes

| Application/Control No. | Applicant(s)/Patent under Reexamination |
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| 09/635,480 | OIKAWA, YUKA |
| Examiner | Art Unit |
| HUY T. NGUYEN | 2621 |

| | SEAR | CHED | |
|-------|----------|-----------|----------|
| Class | Subclass | Date | Examiner |
| 386 | 46 | 4/15/2001 | HN |
| 386 | 80 | | |
| 386 | 81 | | |
| 386 | 74 | | |
| 386 | 104 | | |
| 386 | 124 | | |
| 386 | 68 | V | J |
| 386 | 112 | 4/15/2001 | HN |
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| INTERFERENCE SEARCHED | | | | | |
|-------------------------|----------|---------|----------|--|--|
| Class | Subclass | Date | Examiner | | |
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| Interfere | luce | 4/19/00 | DW | | |
| Interference Sean 15 | | | | | |

| SEARCH NOTES (INCLUDING SEARCH STRATEGY) | | | | | |
|---|---------|------|--|--|--|
| | DATE | EXMR | | | |
| mterference reaks | 4/19/02 | W | | | |
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